

Test Report

No. :KA/2007/61070 Date: 2007/06/20 Page: 1 of 3

RALEC ELECTRONIC CORPORATION
 NO. 1, CENTRAL 2ND STREET, NANTZE EXPORT PROCESSING ZONE,
 KAOHSIUNG, TAIWAN



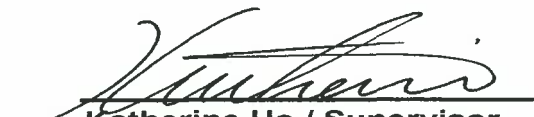
The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : LEAD FREE CHIP RESISTORS ARRAY PRODUCT
 Style/Item No. : RTA03-4C(0603-8P4R)RTA03-4CJ101
 Sample Receiving Date : 2007/06/11
 Testing Period : 2007/06/11 TO 2007/6/20

Test Requested : In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.

Test Method : (1) With reference to US EPA Method 3050B for Lead Content. Analysis was performed by ICP-AES.

Test Result(s) : Please refer to next page(s).



Katherine Ho / Supervisor
Signed for and on behalf of
SGS Taiwan Limited

This Test Report is issued by the Company subject to its General Conditions of Service printed overleaf or available on request and accessible at www.sgs.com. Attention is drawn to the limitations of liability, indemnification and jurisdictional issues defined therein. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this report is unlawful and offenders may be prosecuted to the fullest extent of the law. 此報告是遵循本公司訂定之通用服務條款所製作發放，請注意此條款列印於背面，亦可在www.sgs.com中查閱。將本公司之義務，免責，管轄權皆明確規範之。除非另有說明，此報告結果僅對檢驗之樣品負責。本報告未經本公司書面許可，不可部份複製。對本報告內容或外觀之任何未經授權之變更、偽造、竄改皆屬非法，違犯者將會被依法追究。

TW 5135719